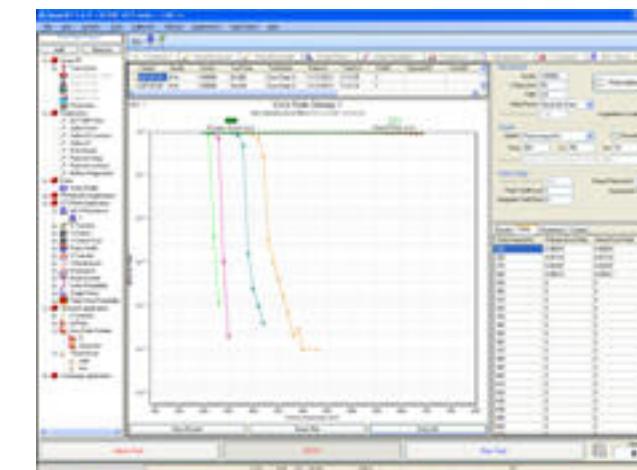


ISI Announces Release of Gen3 Pulser for Worlds First Commercially available fully integrated Wafer Level STT-MRAM Analyzer WLA-3000

SANTA CLARA, CA – Dec 13, 2013: Integral Solutions International, ISI, the world's leading manufacturer of Quasi-Static testers for the data storage industry, announced today the release of Gen3 Pulser Module for WLA-3000 Wafer Level Analyzer for STT-MRAM characterization.

ISI's proprietary Gen3 pulse generator module is optimally matched with its proprietary probecard interface to produce programmable pulses as low as 5nS, with in-situ ability to perform ultra-fast measurements on the MTJs after pulsing. The tester can be equipped with either the single or dual-channel pulse generator modules for improved UPH.

The Gen3 Pulser module was redesigned to speed up Pulse related tests by an order of magnitude. We have added new Error Rate test that allows customers to measure Error Rate of 10^6 in approximately 2 seconds. With such fast Error Rate measurement, customers can now characterize Error Rate as a function of VBias, Pulse Width/Amplitude, Field and other sweep parameters.

**About ISI**

Integral Solutions International (referred to as ISI) is a privately held California based US Corporation. ISI was established in September 1995 and is the leading manufacturer of Quasi-Static testers for GMR, TMR and Perpendicular Heads. This includes a line of Quasi-Static (QST) Testers, ESD and Temperature Stress Testers. ISI's product line of testers consists of Row Bar QST, Slider QST, HGA, HSA, HDA, and Tape Head QST. Optional components include the ESD MR Head Stress System and Temperature Controller System.

ISI provides worldwide customer support from the United States, Japan, Korea, Singapore, Malaysia, Thailand, China, Hong-Kong, and the Philippines.